

<b>Notice of References Cited</b>	Application/Control No. 09/882,290	Applicant(s)/Patent Under Reexamination ISHIDA ET AL.
	Examiner SOPHIA VLAHOS	Art Unit 2637

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	B	US-2002/0103609	08-2002	Kuyel, Turker	702/69
	C	US-2002/0176491	11-2002	Kleck et al.	375/226
	D	US-4,654,861	03-1987	Godard, Dominique	375/226
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Nelson Soo, PERICOM Application Brief AB36, "Jitter Measurement Techniques"
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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